

# **System Overview**

Description	Model				S	erial Number	
$\textbf{CCD Head}  \nabla$	D U 9	U 9 34P - BR-DD			D CCD-17881		
TE Cooler performance (	✔)			High	٦	Ultra-high 🖌	
Accessories	Power Su	Power Supply Unit (PS -24)			PS -25		
					~		
	SO-	LM-		Μ	IFL-		
Serial/Batch Number							
Other							
V Sensor types are defined in Table 1 using the last two letters in box Model Number.							

**CCD** Details

Manufact	urer / Model No.	Pixels	Serial Number
E2V	CCD47-10	1024x1024, 13μm x 13μm	12262-06-07
E2V	CCD57-10	512x512, (FT), 13μm x 13μm	
E2V	CCD77-00	512x512, 24μm x 24μm	

Special Feature	( 🗸 )		( 🖌 )
NIMO		Custom Mounting Flange	
Fringe Suppression		Custom Cables	
Shielded Anti-Blooming			

Window Variant	( 🗸 )		( 🗸 )
VUV-UV Parallel		NUV-Enhanced Parallel	
Broadband VUV-NIR Wedged		Broadband VUV-NIR Parallel	
Broadband VIS-NIR Wedged		Broadband VIS-NIR Parallel	✓
VIS-NIR Enhanced Wedged		Bose-Einstein 780nm Wedged	
None		Other	

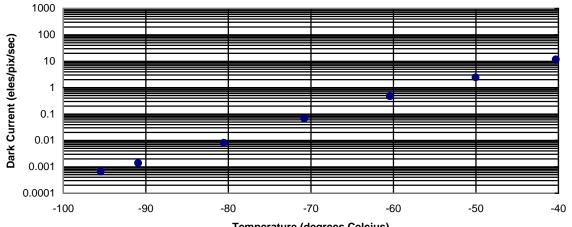


# Summary of System Test Data

#### Readout Noise +1 and Base Mean Level

A/D Rate	Preamp	CCD	Single Pixel	Full Vert Bin	Base Level ♦2
(MHz All 16 bit)	setting	Sensitivity +3	Noise	Noise	(Counts)
		eles per A/D count	electrons	electrons	
5	x1	6.9	35.9	36.1	960
5	x2	3.3	19.9	20.2	1630
5	x4	1.6	15.8	16.2	3147
3	x1	5.9	19.6	19.7	1090
3	x2	3.1	14.1	14.0	2044
3	x4	1.3	10.5	10.5	3757
1	x1	5.4	11.4	11.3	908
1	x2	2.7	8.2	7.9	1845
1	x4	1.3	6.7	6.7	3789
0.05	x1	5.4	5.4	5.4	535
0.05	x2	2.8	4.3	4.3	1445
0.05	x4	1.3	3.8	3.7	3335
Satura	Saturation Signal per pixel			Electror	ns/pixel

#### **CCD Dark Current**



Temperature (degrees Celcius)

Minimum Dark Current Achievable +4	0.000656	electro	ons/pixel/se	ec .
@ Sensor Temperature of ◆5	-95.472	°C	16	°C cooling Water
		With PS	6-25	
CCD Dark Current Uniformity better than +6	0.258933	electro	ons/pixel/se	ec .



# Linearity and Uniformity

Linearity better than •7	1	% over 16 bits
Response Uniformity better than +8	1.89	%

### **Response Defects**

White/Black Spots +	White/Black Spots ♦9 (X,Y)					
Centroid	Number of Pixels	Centro	bid	Number of Pixels		
( X , X )   ( , . )   ( , . )   ( , . )   ( , . )   ( , . )   ( , . )   ( , . )   ( , . )	X	( , , ( , , ( , , ( , , , ,	) ) ) ) )			
White/Black Columns ♦10	Column num	bers indicated	X X	x x		
<b>Trap </b> ♦11		(X,Y)	( X	, X)		

#### **Dark Current Defects**

Hot Spots +12			(X,Y)
Centroid	Number of Pixels	Centroid	Number of Pixels
( X , X ) ( , ) ( , ) ( , ) ( , ) ( , ) ( , )	X	( , , )   ( , , )   ( , , )   ( , , )   ( , , )   ( , , )   ( , , )   ( , , )	
Hot Columns +13	Column num	bers indicated	



# **CCD** PERFORMANCE

# **Test Conditions**

Readout Noise tested at	-80	°C with	16	°C water
Base Mean Level measured at	-80	°C with	16	°C water
Dark Current Uniformity tested at	-65	°C with	16	°C water
Blemishes tested at	-65	°C with	16	°C water

**Custom Testing** 

Signed

System Passed for Shipping

### RAYMOND CLARKE

29TH MAY 2015

Hardware	HEADBOARD	FPGA
Version #	AB	20.24
Shipping Software	SOLIS	SDK
Version #		
Testing Software	SOLIS	SDK
Version #	4.27.30001.0	2.99.33001.0

# $\nabla$ Table 1; Key code to define the meanings of the last two letters in the Model Number

	Sensor Options					
OE	Open electrode	BU2	Back Illuminated (BI) + 250nm UV optimised			
FI	Front illuminated (FI)	BU	BI + UV (350nm) optimised			
UV	FI+UV coating	BV	BI + VIS (550nm) optimised)			
FO	FI + Fibre optic	BR-DD	BI + NIR +deepdepletion			
FI-DD	FI + deep depletion	BN	BI with no AR coating			



# **Performance Notes**

- A Readout Noise is measured for both single pixel (SP) and fully vertically binned (FVB) with the CCD in darkness at temperature indicated and minimum exposure time. Noise values will change with pre-amplifier gain selection [PAG].
- ♦2 Average electronic DC offset for CCD in darkness at temperature indicated and minimum exposure time under dark conditions measured by single pixel (SP) for imaging systems and by (FVB) for spectroscopic systems.
- ♦3 Sensitivity is calculated in photoelectrons per A/D count from measurements of the Photon Transfer Curve.
- ◆4 Dark current falls exponentially with temperature. However, for a given temperature the actual dark current can vary by more than an order of magnitude from device to device. The devices are specified in terms of minimum dark current achievable rather than minimum temperature.
- ♦5 Minimum temperature achieved for thermoelectric (TE) cooler set to maximum value with water cooling
- ♦6 RMS (root mean square) deviation of dark current for fully binned operation for spectroscopic cameras, or full resolution image for imaging cameras, under dark conditions at temperature indicated (pixel/column defects not included). This variation is mainly cosmetic since it is fully subtractable without significant loss of performance.
- ◆7 Linearity is measured from a plot of Counts vs. Signal over the 16 bit dynamic range. Linearity is expressed as a %age deviation from a straight line fit. This quantity is not measured on individual systems.
- ♦8 RMS (root mean square) deviation from the average response of the CCD in full resolution image for imaging cameras, illuminated with uniform white light (defects not included).
- $\bullet$  10 A black column is defined as having ≥ 10 black pixels for imaging cameras.
- ◆11 Pixels which absorb charge as it is clocked through the defective area. When the light source is switched off, the signal from the trap appears to drop off more slowly than the signal from the surrounding pixels.
- ◆ 12 Hot spots are counted if they exhibit >50 times the maximum specified dark current at the test temperature indicated.
- ◆13 A column is considered defective if >10 pixels are affected, or if the column exhibits >2 times the maximum specified dark current at the test temperature indicated.